

TEST REPORT

Report No.: BCTC2607316066-2E

Applicant: GEM One NV

Product Name: RFID Reader

Test Model: SAP-V4-ACC-RFID

Tested Date: 2026-07-23 to 2026-08-07

Issued Date: 2026-08-27



Shenzhen BCTC Technology Co., Ltd.



FCC ID: 2AYCQ-SV4ACCRFID

Product Name: RFID Reader

Trademark: N/A

Model/Type reference: SAP-V4-ACC-RFID

Prepared For: GEM One NV

Address: Brabantstraat 15, 8790 Waregem Belgium

Manufacturer: Secukey Technology Co.,Ltd.

Address: Floor 5, Building 13, Longbi Industrial Park, Bantian Sub District, Longgang District, Shenzhen, China.

Prepared By: Shenzhen BCTC Technology Co., Ltd.

Address: Room 101M, Unit 1, Building1, Pengyuan, No.18, Lilang Road, Shanglilang, Nanwan Subdistrict, Longgang District, Shenzhen, Guangdong, China.

Sample Received Date: 2026-07-22

Sample tested Date: 2026-07-23 to 2026-08-07

Report No.: BCTC2607316066-2E

Test Standards: FCC CFR 47 part1, 1.1307(b), 1.1310
KDB 680106 D01 Wireless Power Transfer v04

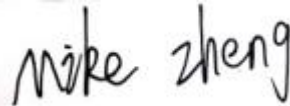
Test Results: PASS

Prepared by :



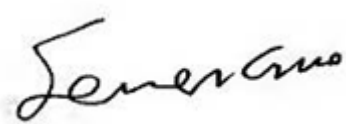
Eric Yang

Reviewer by :



Mike Zheng

Approved by:



Sewen Guo

The test report is effective only with both signature and specialized stamp. This result(s) shown in this report refer only to the sample(s) tested. Without written approval of Shenzhen BCTC Technology Co., Ltd, this report can't be reproduced except in full. The tested sample(s) and the sample information are provided by the client.

Table Of Content

Test Report Declaration	Page
1. Version	4
2. Product Information	5
2.1 Product Information	5
2.2 Test Setup Configuration	5
2.3 Support Equipment	6
2.4 Test Mode	6
3. Test Facility And Test Instrument Used	7
3.1 Test Facility	7
3.2 Test Instrument Used	7
4. Method Of Measurement	8
4.1 Applicable Standard	8
4.2 Block Diagram Of Test Setup	8
4.3 Limit	9
4.4 Test procedure	9
4.5 E and H field Strength	10
5. Photographs Of Test Set-Up	13

(Note: N/A Means Not Applicable)

1. Version

Report No.	Issue Date	Description	Approved
BCTC2309647432-1E	2026-08-27	Original	Valid

2. Product Information

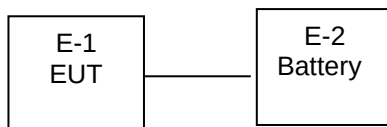
2.1 Product Information

Model/Type reference:	SAP-V4-ACC-RFID
Model differences:	N/A
Operation Frequency:	125KHz
Type of Modulation:	ASK
Antenna installation:	loop coil antenna
Ratings:	DC 12V

2.2 Test Setup Configuration

See test photographs attached in *EUT TEST SETUP PHOTOGRAPHS* for the actual connections between Product and support equipment.

Radiated Spurious Emission:



2.3 Support Equipment

No.	Device Type	Brand	Model	Series No.	Note
E-2	Battery	N/A	57069	N/A	Auxiliary

Notes:

1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

2.4 Test Mode

Test Mode 1	TX
-------------	----

3. Test Facility And Test Instrument Used

3.1 Test Facility

All measurement facilities used to collect the measurement data are located at Shenzhen BCTC Technology Co., Ltd.

Address: Room 101M, Unit 1, Building1, Pengyuan, No.18, Lilang Road, Shanglilang, Nanwan Subdistrict, Longgang District, Shenzhen, Guangdong, China.

The site and apparatus are constructed in conformance with the requirements of ANSI C63.4a-2017 and CISPR 16-1-1:2019 other equivalent standards.

FCC Test Firm Registration Number: 754702

ANAB certificate registration number is: CN3479

3.2 Test Instrument Used

Name of instrument	Model	Manufacturer	Cal. Date	Due Date
Electro magnetic radiation tester	SMP160	Wavecontrol	2026.05.12	2027.05.13

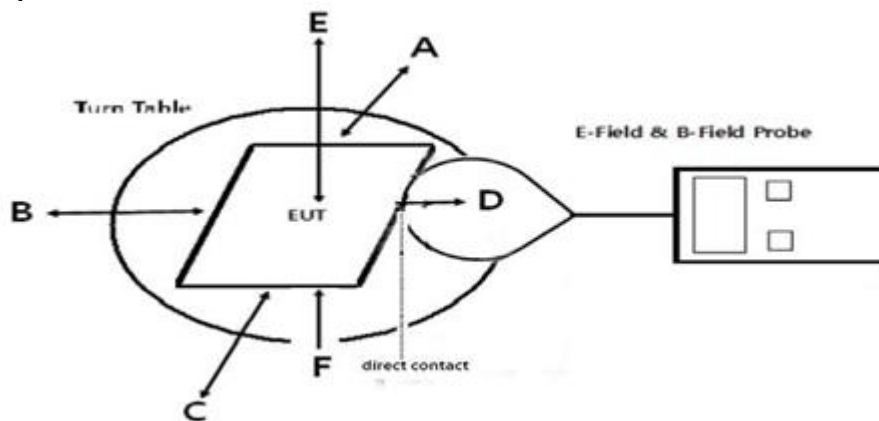
4. Method Of Measurement

4.1 Applicable Standard

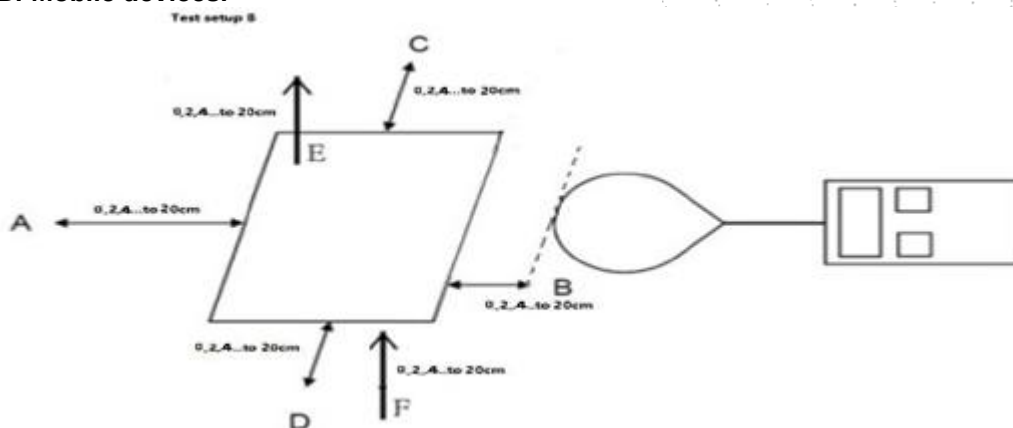
According to §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines. According to §1.1310 and §2.1093 RF exposure is calculated. According KDB680106 D01v04: RF Exposure Wireless Charging Apps v04.

4.2 Block Diagram Of Test Setup

A: portable devices.



B: Mobile devices.



4.3 Limit

Limits for Occupational / Controlled Exposure				
Frequency Range (MHz)	Electric Field Strength (E) (V/m)	Magnetic Field Strength (H) (A/m)	Power Density (S) (mW/ cm ²)	Averaging Time E ² , H ² or S (minutes)
0.3-3.0	614	1.63	(100)*	6
3.0-30	1842 / f	4.89 / f	(900 / f)*	6
30-300	61.4	0.163	1.0	6
300-1500			F/300	6
1500-100,000			5	6

Limits for General Population / Uncontrolled Exposure				
Frequency Range (MHz)	Electric Field Strength (E) (V/m)	Magnetic Field Strength (H) (A/m)	Power Density (S) (mW/ cm ²)	Averaging Time E ² , H ² or S (minutes)
0.3-1.34	614	1.63	(100)*	30
1.34-30	824/f	2.19/f	(180 / f)*	30
30-300	27.5	0.073	0.2	30
300-1500			F/1500	30
1500-100,000			1	30

4.4 Test procedure

- The RF exposure test was performed in anechoic chamber.
- The EUT was measured according to the dictates of KDB680106 D01v04
- Remark:The EUT's test position A, B, C, D , E and F is valid for the E and H field measurements.

4.5 E and H field Strength

Mobile: Test Mode 1

H-Filed Strength at (distance from 0cm to 20cm at 2cm iteration) surrounding the EUT (A/m)

Test distance (cm)	Test Position A(uT)	Test Position B(uT)	Test Position C(uT)	Test Position D(uT)	Test Position E(uT)	Test Position F(uT)
2	0.0858	0.0840	0.0833	0.0789	0.0958	0.0644
4	0.0884	0.0737	0.0764	0.0852	0.0400	0.0207
6	0.0456	0.0880	0.0635	0.0975	0.0402	0.0278
8	0.0541	0.0679	0.0665	0.0822	0.0500	0.0248
10	0.0391	0.0645	0.0633	0.0931	0.0413	0.0124
12	0.0548	0.0590	0.0762	0.0799	0.0607	0.0209
14	0.0280	0.0572	0.0789	0.0782	0.0268	0.0269
16	0.0275	0.0653	0.0843	0.0815	0.0220	0.0218
18	0.0353	0.0772	0.0786	0.0781	0.0348	0.0136
20	0.0416	0.0589	0.0980	0.0810	0.0329	0.0133

Test distance (cm)	Test Position A(A/m)	Test Position B(A/m)	Test Position C(A/m)	Test Position D(A/m)	Test Position E(A/m)	Test Position F(A/m)	Limits (A/m)
2	0.0686	0.0672	0.0667	0.0631	0.0767	0.0516	1.63
4	0.0707	0.0590	0.0611	0.0682	0.0320	0.0166	1.63
6	0.0365	0.0704	0.0508	0.0780	0.0321	0.0223	1.63
8	0.0432	0.0543	0.0532	0.0657	0.0400	0.0198	1.63
10	0.0312	0.0516	0.0506	0.0745	0.0330	0.0099	1.63
12	0.0439	0.0472	0.0610	0.0639	0.0486	0.0167	1.63
14	0.0224	0.0457	0.0631	0.0626	0.0214	0.0215	1.63
16	0.0220	0.0522	0.0675	0.0652	0.0176	0.0174	1.63
18	0.0282	0.0617	0.0628	0.0625	0.0278	0.0109	1.63
20	0.0333	0.0471	0.0784	0.0648	0.0263	0.0107	1.63

Note: A/m=uT/1.25

Using Biot-Savart Law, the value of 0cm can be estimated through the test results of 2cm:
Distance: 0cm

Battery	Test Position A(A/m)	Test Position B(A/m)	Test Position C(A/m)	Test Position D(A/m)	Test Position E(A/m)	Test Position F(A/m)	Limits (A/m)
99%	0.1107	0.0940	0.0764	0.0991	0.0987	0.1001	1.63

Using Biot-Savart Law, the value of 2cm can be estimated through the test results of 4cm:
Distance: 2cm

Battery	Test Position A(A/m)	Test Position B(A/m)	Test Position C(A/m)	Test Position D(A/m)	Test Position E(A/m)	Test Position F(A/m)	Limits (A/m)
99%	0.0665	0.0592	0.0648	0.0628	0.0725	0.0505	1.63

Agreement Ratio
Distance: 2cm

Mode 1				
Test Position	Measure Value (A/m)	Valuation(A/m)	Agreement ratio	Limit
A	0.0686	0.0665	3.11%	30%
B	0.0672	0.0592	12.66%	30%
C	0.0667	0.0648	2.89%	30%
D	0.0631	0.0628	0.48%	30%
E	0.0767	0.0725	5.63%	30%
F	0.0516	0.0505	2.15%	30%
Test result: Pass				

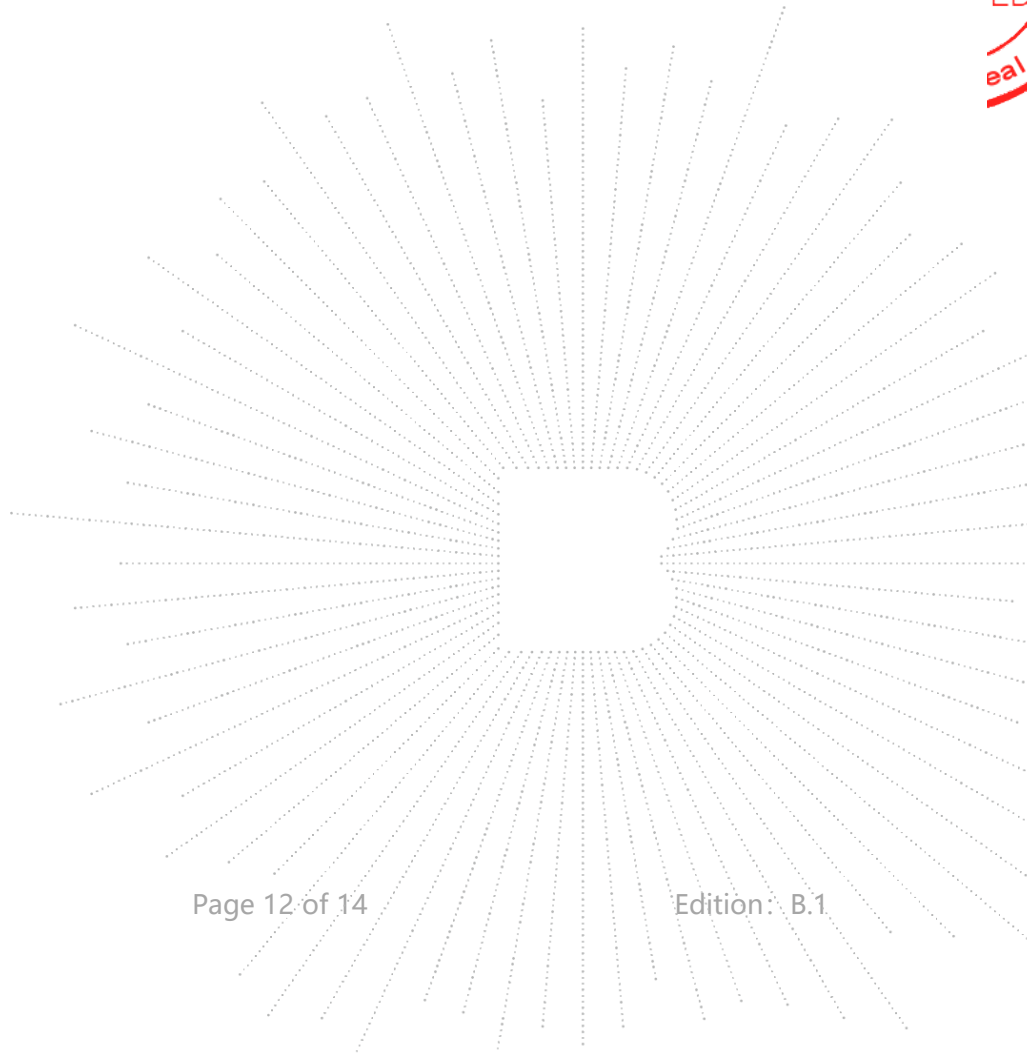
Using Biot-Savart Law, the value of 4cm can be estimated through the test results of 6cm:
Distance: 4cm

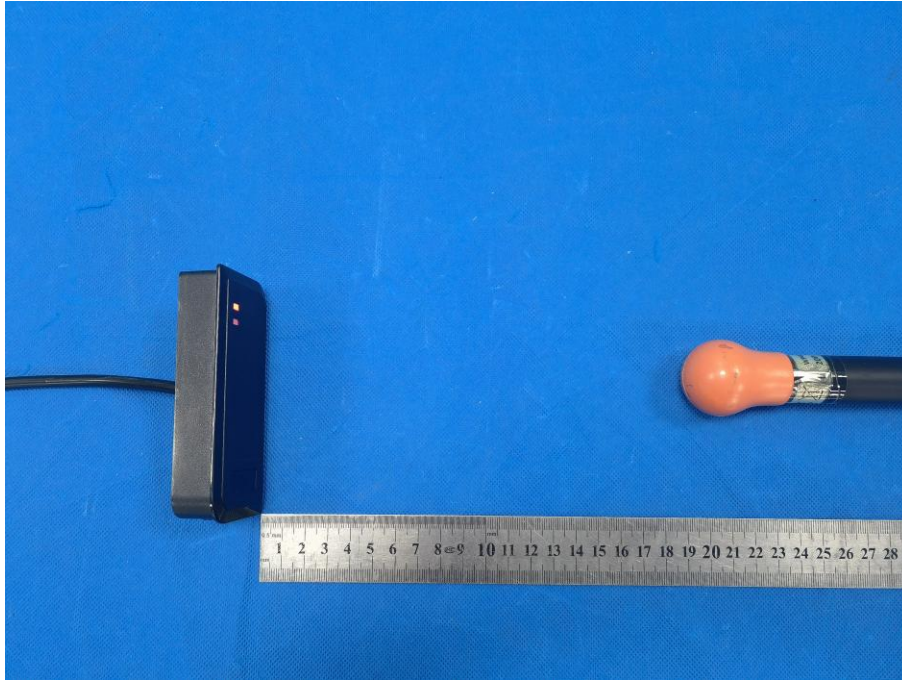
Battery	Test Position A(A/m)	Test Position B(A/m)	Test Position C(A/m)	Test Position D(A/m)	Test Position E(A/m)	Test Position F(A/m)	Limits (A/m)
99%	0.065	0.055	0.06	0.0628	0.0258	0.0135	1.63

Agreement Ratio
Distance: 4cm

Mode 1				
Test Position	Measure Value (A/m)	Valuation(A/m)	Agreement ratio	Limit
A	0.0707	0.065	8.4%	30%
B	0.0590	0.055	7.02%	30%
C	0.0611	0.06	1.82%	30%
D	0.0682	0.0628	8.24%	30%
E	0.0320	0.0258	21.45%	30%
F	0.0166	0.0135	20.6%	30%
Test result: Pass				

INNOVATION
C
ED
real



5. Photographs Of Test Set-Up

STATEMENT

1. The equipment lists are traceable to the International System of Units (SI)
2. The test report can not be partially copied unless prior written approval is issued from our lab.
3. The test report is invalid without the "special seal for inspection and testing".
4. The test report is invalid without the signature of the approver.
5. The test process and test result is only related to the Unit Under Test.
6. Sample information is provided by the client and the laboratory is not responsible for its authenticity.
7. The quality system of our laboratory is in accordance with ISO/IEC 17025:2017.
8. If there is any objection to this test report, the client should inform issuing laboratory within 15 days from the date of receiving test report.

Address:

Room 101M, Unit 1, Building1, Pengyuan, No.18, Lilang Road, Shanglilang, Nanwan Subdistrict, Longgang District, Shenzhen, Guangdong, China

TEL: 400-788-9558

P.C.: 518103

FAX: 0755-33229357

Website: <http://www.chnbctc.com>

Consultation E-mail: bctc@bctc-lab.com.cn

Complaint/Advice E-mail: advice@bctc-lab.com.cn

***** END *****